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(12) **United States Design Patent**
Tackett et al.

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(54) **TRACE ANALYSIS INSTRUMENT**

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(**) Term: **15 Years**

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(52) **U.S. Cl.**
USPC **D10/81**
(58) **Field of Classification Search**
USPC D10/78, 81
CPC G01N 30/72; G01N 30/02; G01N 30/7206; G01N 30/88; G01N 2030/0095; G01N 27/16; G01N 27/18; G01N 27/185; G01N 33/0006; G01N 33/0009–33/0075; G01N 1/24; G01N 1/2205; G01N 1/2273; G01N 2001/2276; G01N 23/10; G01N 23/223; G01N 2223/076; G01N 29/226; G01N 2223/0763; G01N 2223/0766; G01N 21/8483; G01N 21/84; G01N 21/77; G01N 21/78; G01N 21/94; G01N 21/01; G01N 21/6428; G01N 21/643; G01N 21/293; G01N 21/33; G01N 1/02; G01N 35/00009; G01N 35/1095; G01N 2001/024; G01N 2001/028; G01N 2001/022; G01N 2001/2833; G01N 2001/007; G01N 2001/021; G01N 2021/7786; G01N 2021/7733; G01N 33/0057; G01N 33/227; G01N 33/22; G01N 33/0032; G01N 31/22; G01N 2201/0221; G01D 11/24; G08B 17/10–17/117; H05G 1/02; H05G 1/06; H05G 1/023; A61B 10/0045; A61B 10/0051; A61B 2010/0006; A61B 2010/0009; G06K 9/00
See application file for complete search history.

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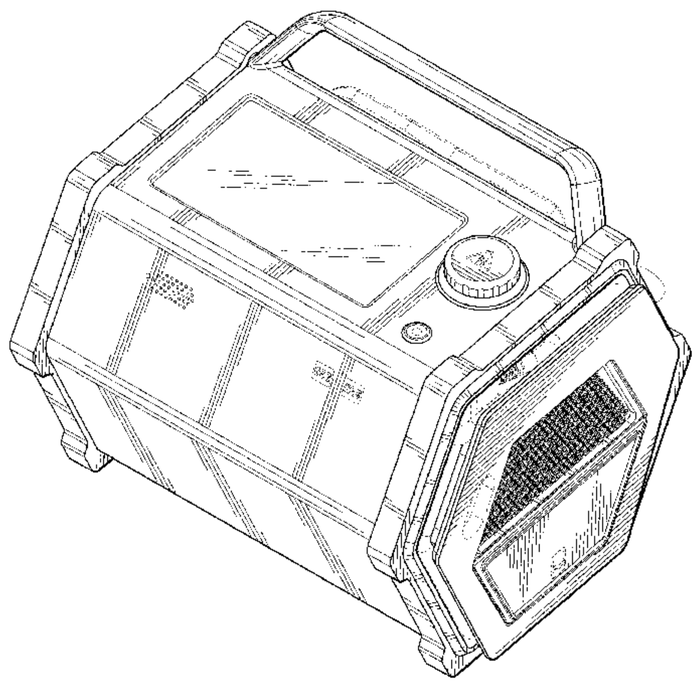
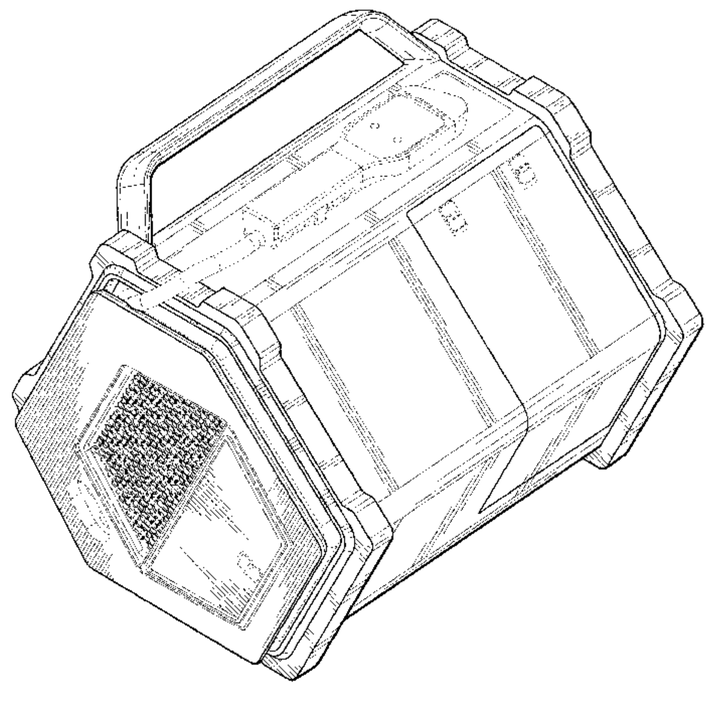
(57) **CLAIM**

The ornamental design for a trace analysis instrument, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of the trace analysis instrument embodying our new design.
FIG. **2** is a side elevational view thereof.
FIG. **3** is a side elevational view thereof.
FIG. **4** is a top plan view thereof.
FIG. **5** is a bottom plan view thereof.
FIG. **6** is a side elevational view thereof.
FIG. **7** is a side elevational view thereof; and,
FIG. **8** is another perspective view thereof.
(Continued)





The broken lines in the figures are shown for the purpose of illustrating portions of the trace analysis instrument and/or environmental matter and form no part of the claimed design.

1 Claim, 8 Drawing Sheets

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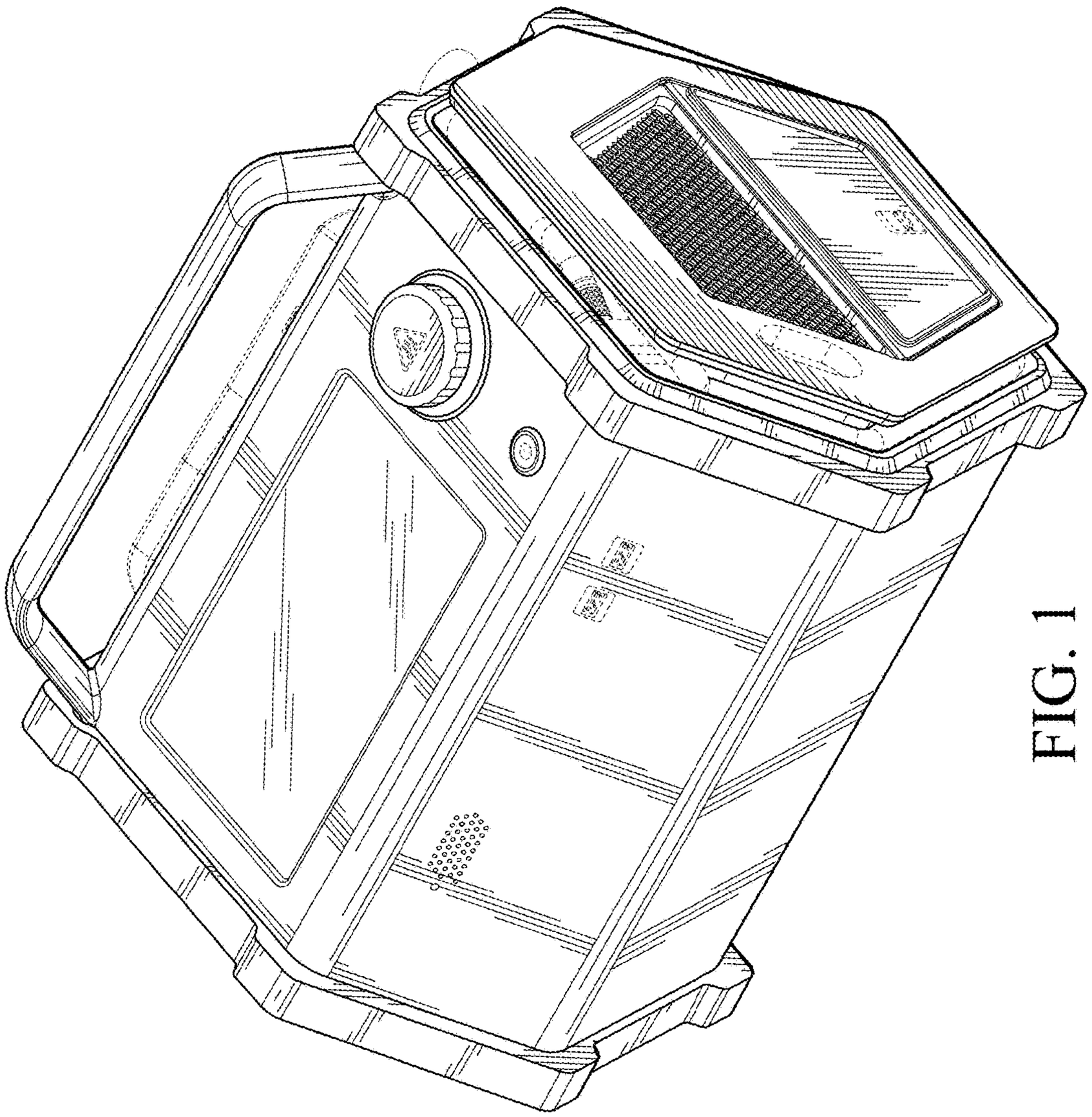

FIG. 1

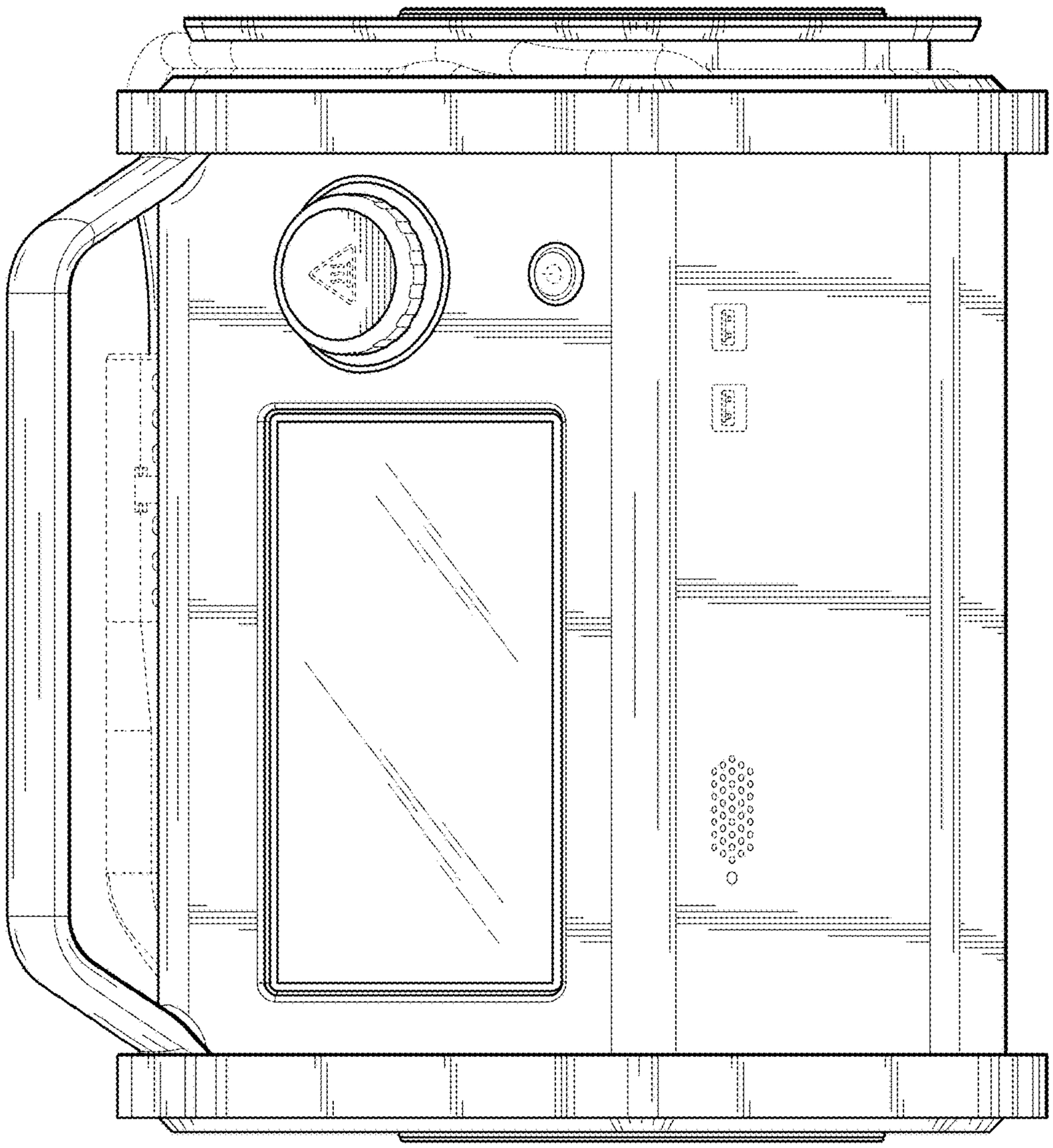

FIG. 2

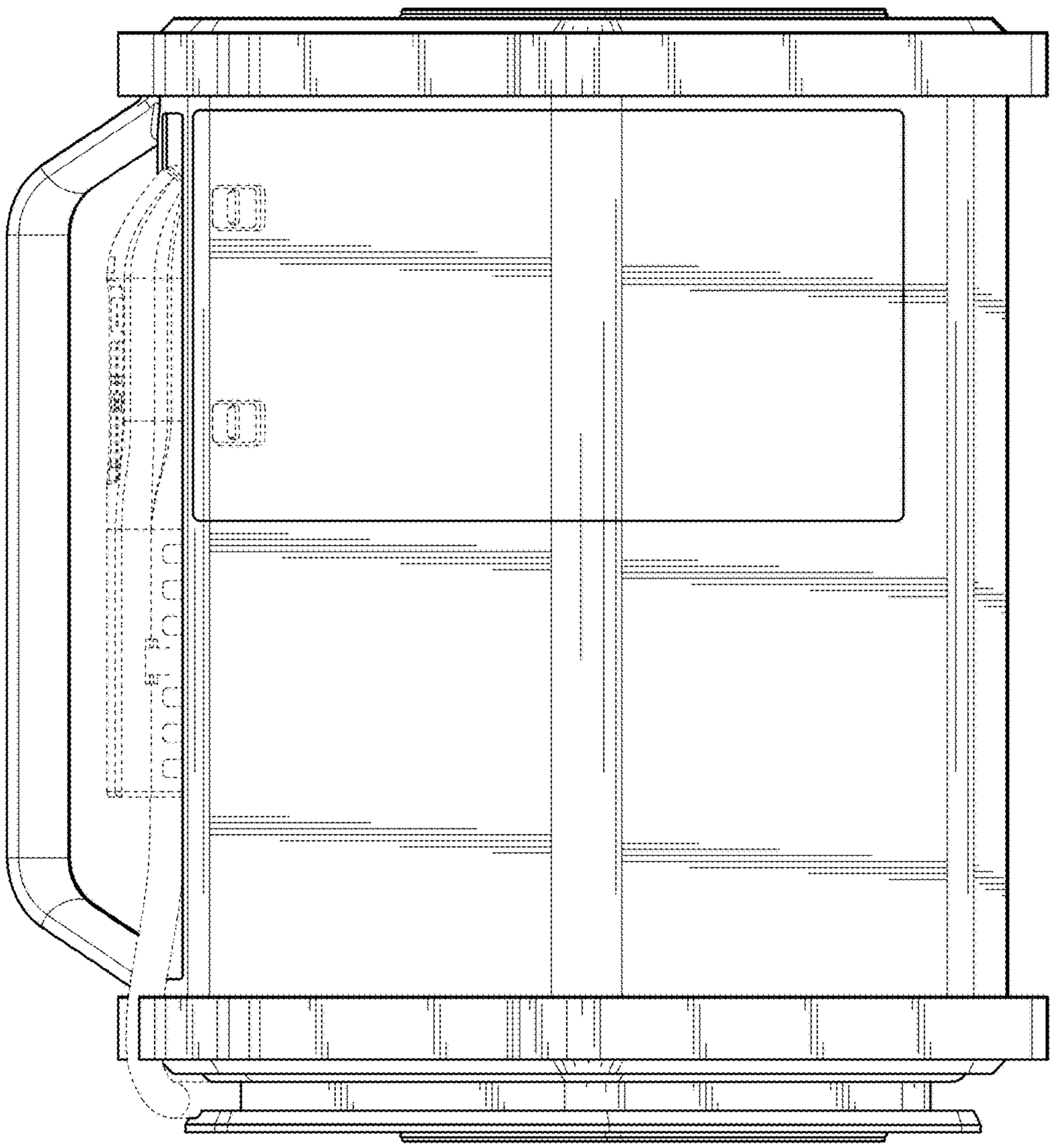

FIG. 3

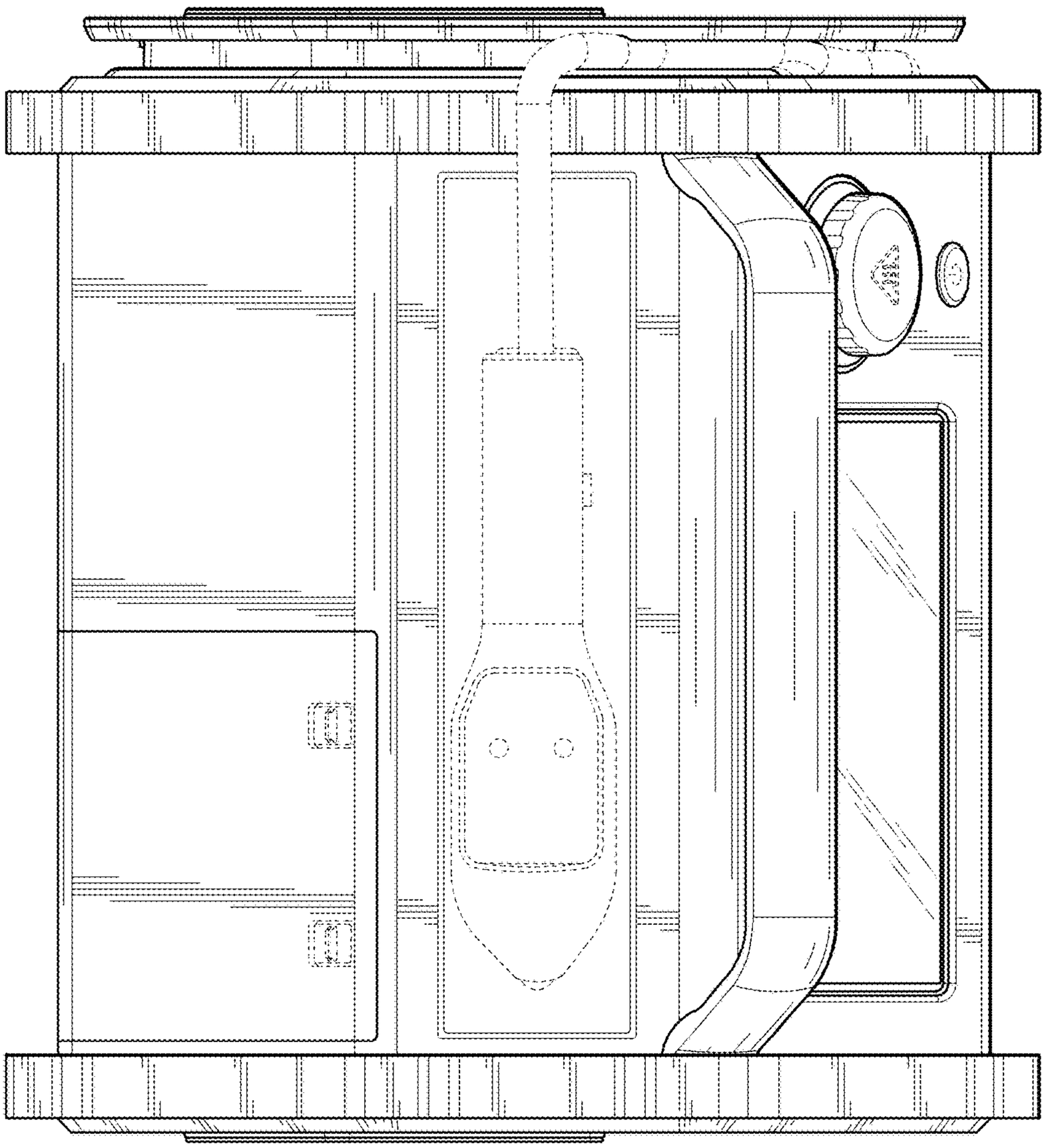

FIG. 4

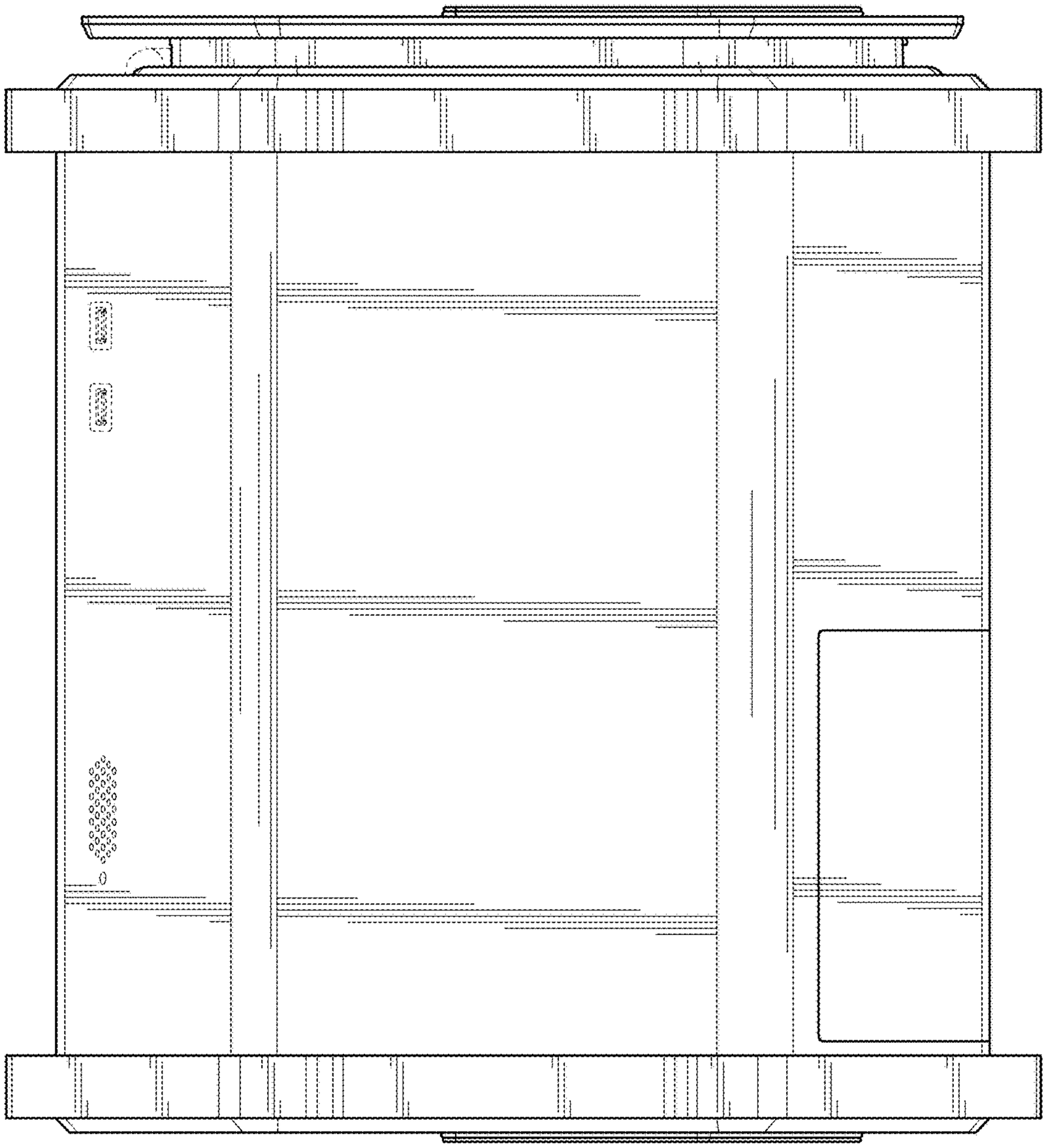

FIG. 5

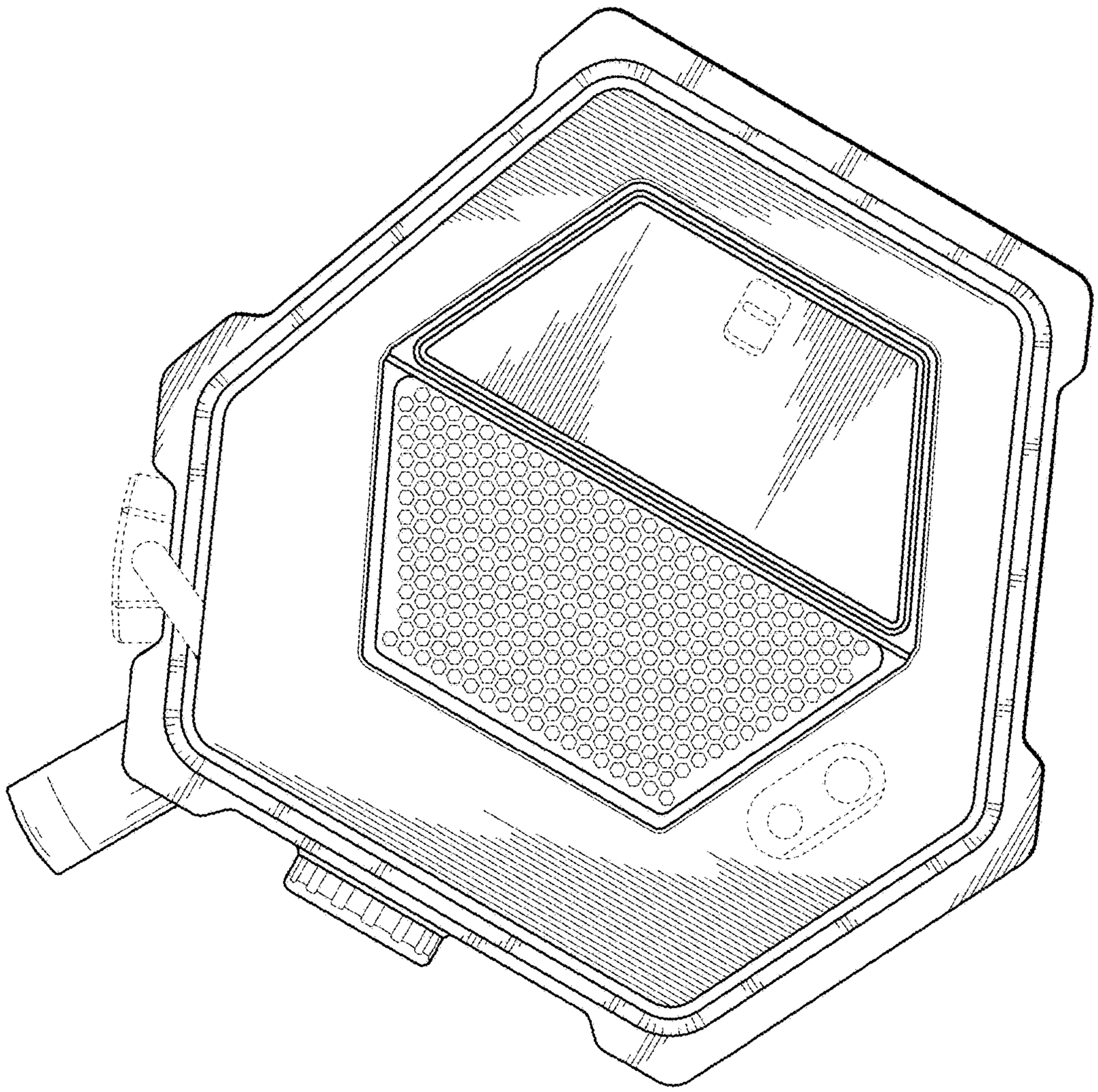

FIG. 6

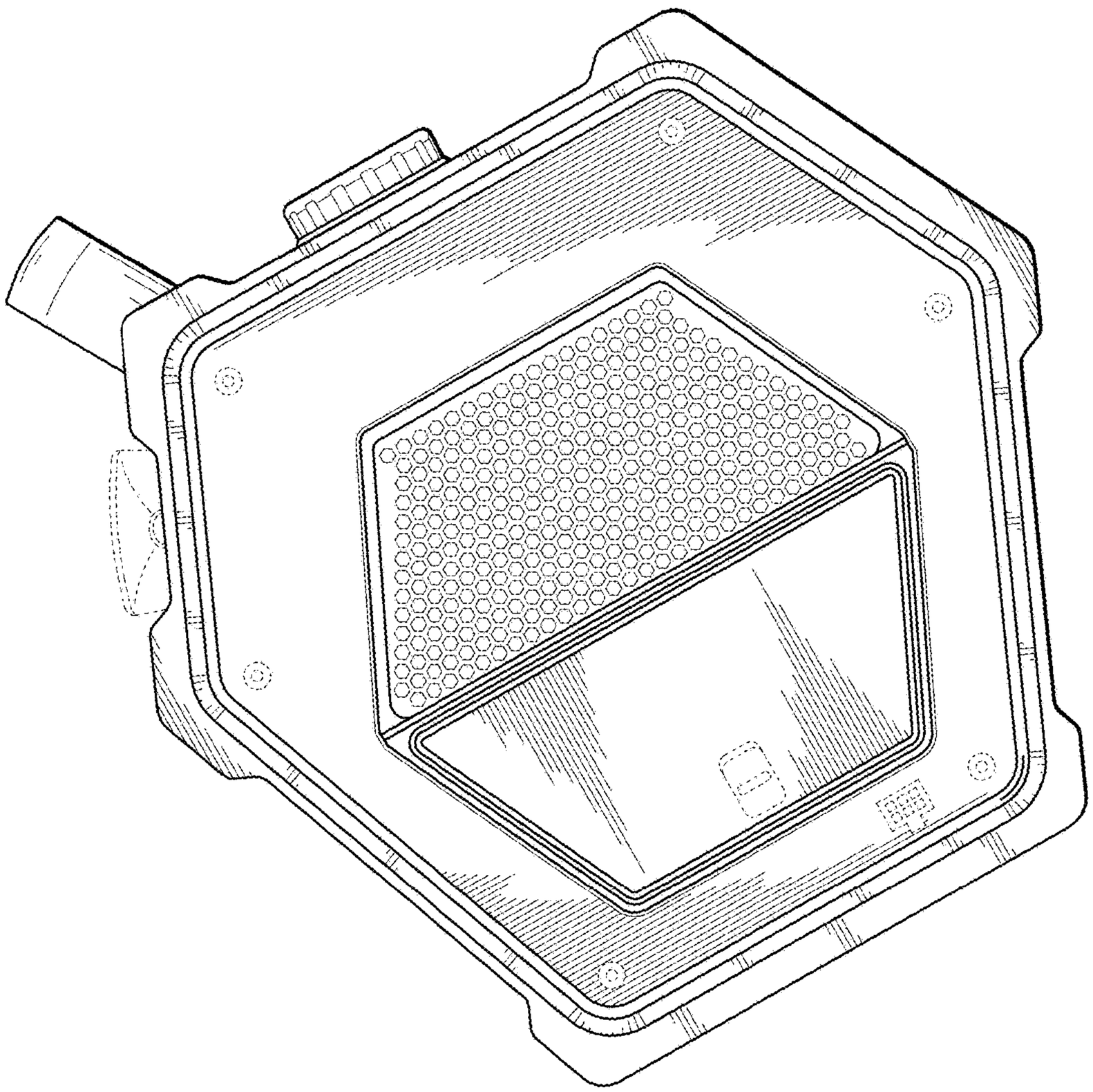

FIG. 7

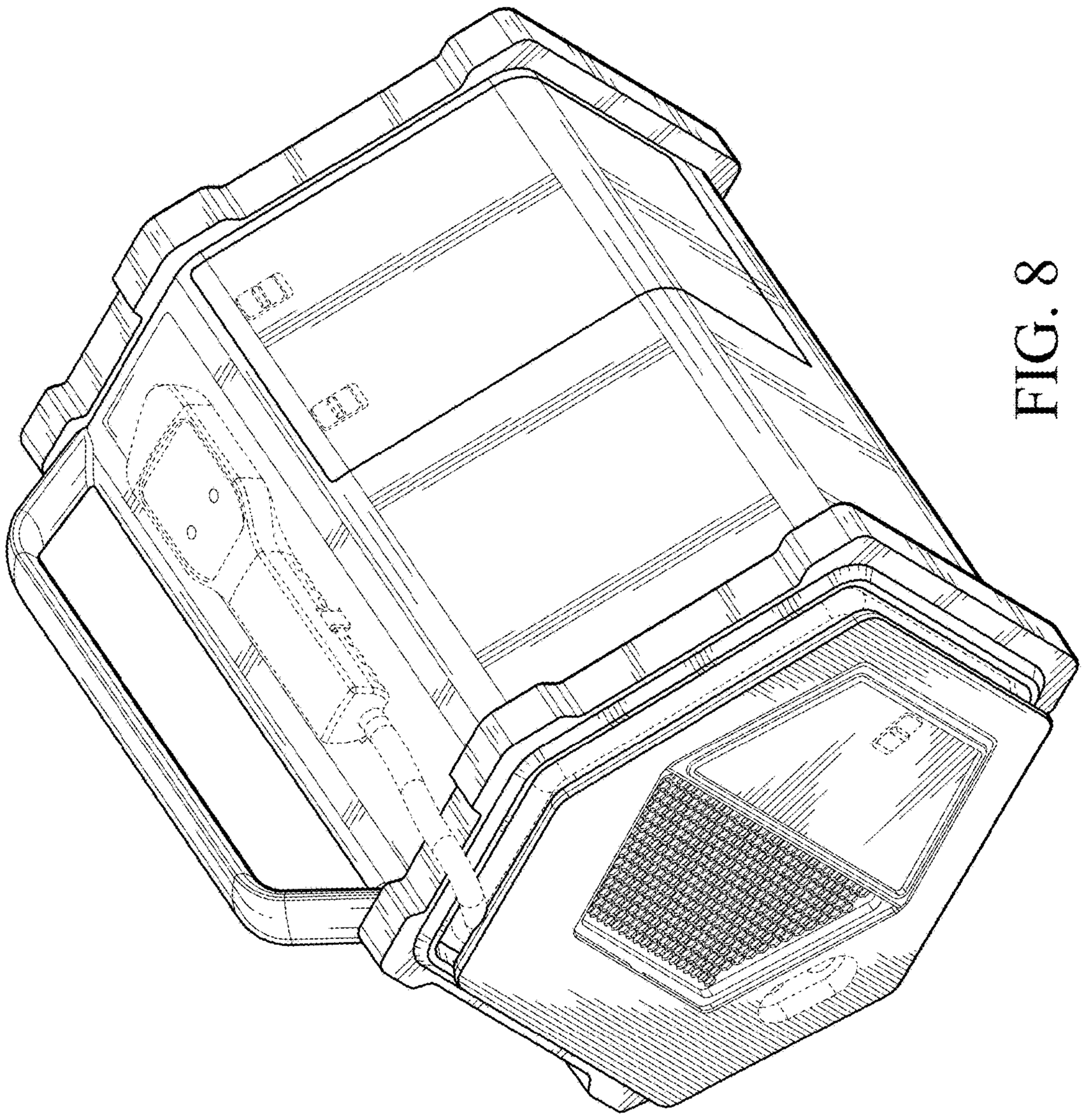

FIG. 8